

ACS245MS

Radiation Hardened Octal Non-Inverting Bidirectional Bus Transceiver

Pinouts

January 1996

Features

- Devices QML Qualified in Accordance with MIL-PRF-38535
- Detailed Electrical and Screening Requirements are Contained in SMD# 5962-96707 and Intersil' QM Plan
- 1.25 Micron Radiation Hardened SOS CMOS
- Single Event Upset (SEU) Immunity: <1 x 10⁻¹⁰ Errors/Bit/Day (Typ)

- Latch-Up Free Under Any Conditions
- Significant Power Reduction Compared to ALSTTL Logic
- DC Operating Voltage Range 4.5V to 5.5V
- Input Logic Levels
 - VIL = 30% of VCC Max
 - VIH = 70% of VCC Min
- Input Current \leq 1µA at VOL, VOH
- Fast Propagation Delay..... 15ns (Max), 10ns (Typ)

Description

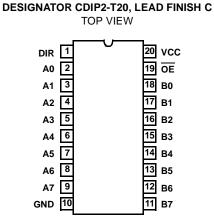
The Intersil ACS245MS is a Radiation Hardened octal non-inverting bidirectional bus transceiver intended for two-way asynchronous communication between data busses.

The ACS245MS utilizes advanced CMOS/SOS technology to achieve high-speed operation. This device is a member of radiation hardened, high-speed, CMOS/SOS Logic Family.

The ACS245MS is supplied in a 20 lead Ceramic Flatpack (K suffix) or a Dual-In-Line Ceramic Package (D suffix).

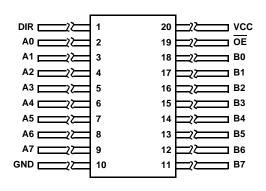
Ordering Information

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PART NUMBER	TEMPERATURE RANGE	SCREENING LEVEL	PACKAGE
5962F9670701VRC	-55°C to +125°C	MIL-PRF-38535 Class V	20 Lead SBDIP
5962F9670701VXC	-55°C to +125°C	MIL-PRF-38535 Class V	20 Lead Ceramic Flatpack
ACS245D/Sample	25°C	Sample	20 Lead SBDIP
ACS245K/Sample	25°C	Sample	20 Lead Ceramic Flatpack
ACS245HMSR	25°C	Die	Die



20 PIN CERAMIC DUAL-IN-LINE, MIL-STD-1835

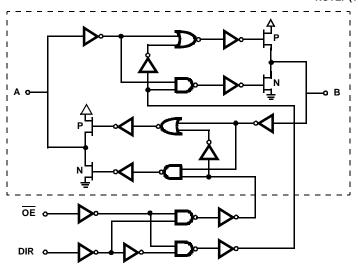
20 PIN CERAMIC FLATPACK, MIL-STD-1835 DESIGNATOR CDFP4-F20, LEAD FINISH C TOP VIEW



CAUTION: These devices are sensitive to electrostatic discharge; follow proper IC Handling Procedures. 1-888-INTERSIL or 321-724-7143 | Copyright © Intersil Corporation 1999

Functional Diagram

NOTE: (1 of 8)



TRUTH TABLE

INP		
OE	DIR	OPERATION
L	L	B Data to A Bus
L	Н	A Data to B Bus
Н	Х	Isolation

NOTE:

H = High Voltage Level, L = Low Voltage Level, X = Immaterial

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Die Characteristics

DIE DIMENSIONS:

96 mils x 117 mils 2.44mm x 2.97mm

METALLIZATION:

Type: AlSi Metal 1 Thickness: 7.125kÅ ±1.125kÅ Metal 2 Thickness: 9kÅ ±1kÅ

GLASSIVATION:

Type: SiO₂ Thickness: 8kÅ ±1kÅ

WORST CASE CURRENT DENSITY:

 $< 2.0 \text{ x} 10^{5} \text{A/cm}^{2}$

BOND PAD SIZE:

110μm x 110μm 4.4 mils x 4.4 mils

Metallization Mask Layout

